Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/750,355	MATHIEU ET AL.	
Examiner	Art Unit	
Edwin A. León	2833	

SEARCHED				
Class	Subclass	Date	Examiner	
439 	66	3/11/2005	EAL	
	862			
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V	515		V	
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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